

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/780,939	LEE, CHANG-KYU	
Examiner	Art Unit	
James D. Ewart	2683	

	SEARCHED			
Class	Subclass	Date	Examiner	
455	9	10/13/2005	JDE	
	13.3			
	26.1			
	63.4			
	67.11			
	68			
	82			
	115.1			
	115.4			
	121			
	123			
	129			
	193.1			
	226.1			

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

(INCLUDING SEA	RCH STRATEG	Y)
	DATE	EXMR
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Search Notes (continued)



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10/780,939	LEE, CHANG-K	YU
Examiner	Art Unit	
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SEARCHED			
Class	Subclass	Date	Examiner
455	423	10/13/2005	JDE
	562.1		
	550.1		
	575.7		
343	703		
	711		
	751		
	893		
	894		
	876		
342	173		
	423		
	444		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
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